SN74AS1008A QUADRUPLE 2-INPUT POSITIVE-AND BUFFER/DRIVER

SDAS071B - DECEMBER 1982 - REVISED JANUARY 1995

- Driver Version of 'AS08
- Offers High Capacitive-Drive Capability
- Package Options Include Plastic Small-Outline (D) Packages and Standard Plastic (N) 300-mil DIPs

description

This device contains four independent 2-input positive-AND buffers/drivers. It <u>performs</u> the Boolean functions $Y = A \bullet B$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN74AS1008A is characterized for operation from 0° C to 70° C.

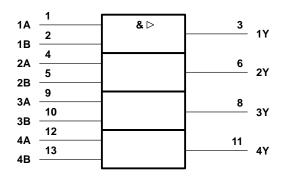
D OR N PACKAGE (TOP VIEW) 1A □ V_{CC} 1B 13 🛮 4B 2 1Y 12 T 4A 3] 4Y 2A 11 2B ∏ 3B 10 2Y 9 3A 6 8 **∏** 3Y GND

FUNCTION TABLE (each gate)

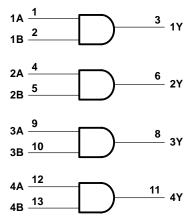
INPUTS		OUTPUT
Α	В	Y
Н	Н	Н
L	X	L
Х	L	L

logic symbol†

logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



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recommended operating conditions†

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ЮН	High-level output current			-48	mA
l _{OL}	Low-level output current			48	mA
TA	Operating free-air temperature	0		70	°C

[†] This high sink- or source-current device is not recommended for use above 40 MHz.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
VIK	$V_{CC} = 4.5 V$,	I _I = -18 mA			-1.2	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			
VOH	V 45V	$I_{OH} = -3 \text{ mA}$	2.4	3.2		V
	V _{CC} = 4.5 V	$I_{OH} = -48 \text{ mA}$	2			
V _{OL}	$V_{CC} = 4.5 V,$	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lį	$V_{CC} = 5.5 V$,	V _I = 7 V			0.1	mA
I _{IH}	$V_{CC} = 5.5 V$,	V _I = 2.7 V			20	μΑ
I _{IL}	$V_{CC} = 5.5 V,$	V _I = 0.4 V			-0.5	mA
ΙΟ§	$V_{CC} = 5.5 V,$	V _O = 2.25 V	-50		-200	mA
Іссн	$V_{CC} = 5.5 V,$	V _I = 4.5 V		5.6	9.5	mA
ICCL	$V_{CC} = 5.5 V$,	V _I = 0		13.5	22	mA

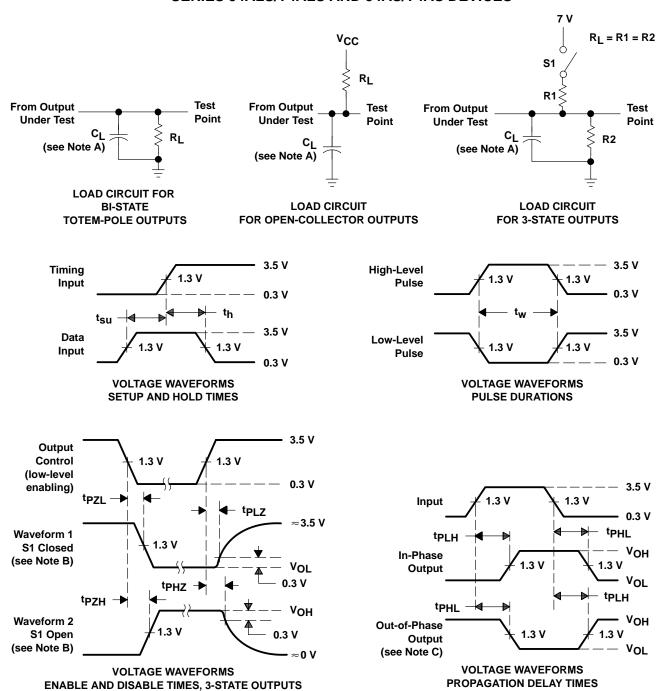
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω , T_A = MIN to MAX¶		UNIT
t _{PLH}	A or B	V	1	6	
^t PHL		1	1	6	ns

[¶] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C. § The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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